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Just  
Got Better!*

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# Powder Diffraction File™ Databases & JADE® Software



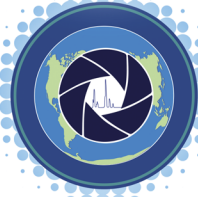
**PDF-5+**  
The Next-Level Database



**PDF-5+/Web**  
Data on the Go



**PDF-4/Axiom**  
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Mineral Collection



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**PDF-2**  
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**JADE Pro**  
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Introducing the 2024 Powder Diffraction File™

*The Best Just Got Better!*



# PDF-5+

## The Next-Level Database

PDF-5+ is the world's most comprehensive Powder Diffraction File™ (PDF®) database with 1,060,000+ entries! Combining ICDD's PDF-4+ and PDF-4/Organics databases, PDF-5+ contains 442,600+ inorganic and 623,000+ organic entries to ensure that you have the data you need for all of your phase identification needs. With every entry editorially reviewed and assigned quality marks, the curated PDF-5+ database allows users to do quantitative analysis by any of three methods: Rietveld Analysis, Reference Intensity Ratio (RIR) Method, or Whole Pattern Fitting.

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## KEY POINTS

- Featuring 1,061,890+ Entries, including 586,700+ Entries with Atomic Coordinates, 623,050+ Organic Entries
- Combines Powder and Single Crystal Data
- Analyze X-ray, Synchrotron, Electron & Neutron Data
- Digitized Patterns
- Molecular Graphics



\*Also available on USB & DVD



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